TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (L²-π-MOSV)

2SJ412

DC-DC Converter, Relay Drive and Motor Drive Applications

- 4-V gate drive
- Low drain-source ON resistance: RDS (ON) = 0.15Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 7.7 \text{ S (typ.)}$
- Low leakage current: $IDSS = -100 \mu A \text{ (max) (VDS} = -100 \text{ V)}$
- Enhancement mode: $V_{th} = -0.8$ to -2.0 V ($V_{DS} = -10$ V, $I_{D} = -1$ mA)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	-100	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	-100	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	-16	А	
	Pulse (Note 1)	I _{DP}	-64		
Drain power dissipation	n (Tc = 25°C)	P _D	60	W	
Single pulse avalanche energy (Note 2)		E _{AS}	292	mJ	
Avalanche current		I _{AR}	-16	Α	
Repetitive avalanche e	energy (Note 3)	E _{AR}	6	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	2.08	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	83.3	°C/W

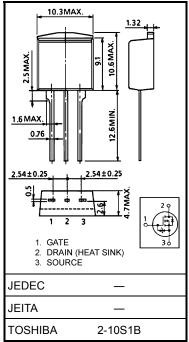
Note1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = -25 V, T_{ch} = 25°C (initial), L = 1.84 mH, R_G = 25 Ω , I_{AR} = -16 A

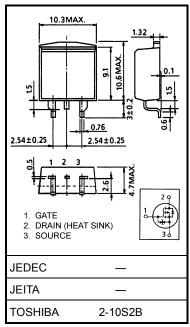
Note 3: Repetitive rating: pulse width limited by maximum junction temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm



Weight: 1.5 g (typ.)



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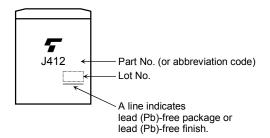
Electrical Characteristics (Ta = 25°C)

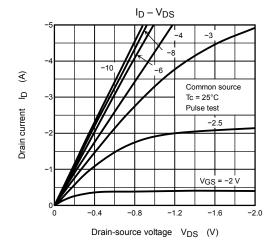
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off curre	ent	I _{DSS}	V _{DS} = -100 V, V _{GS} = 0 V	_	_	-100	μΑ
Drain-source brea	akdown voltage	V (BR) DSS	I _D = -10 mA, V _{GS} = 0 V	-100	_	_	V
Gate threshold vo	oltage	V _{th}	V _{DS} = −10 V, I _D = −1 mA	-0.8	_	-2.0	V
Cata aguras ON	raciatanaa	_	V _{GS} = -4 V, I _D = -6 A	_	0.25	0.32	
Gate-source ON resistance		R _{DS} (ON)	V _{GS} = -10 V, I _D = -6 A	_	0.15	0.21	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = -10 V, I _D = -6 A	4.5	7.7	_	S
Input capacitance	•	C _{iss}		-	1100	_	pF
Reverse transfer capacitance		C _{rss}	V _{DS} = -10 V, V _{GS} = 0 V, f = 1 MHz	_	210	_	pF
Output capacitance		C _{oss}		_	440	_	pF
Switching time	Rise time	t _r	V _{GS} -10 V	_	18	_	
	Turn-on time	t _{on}		_	30	_	
	Fall time	t _f		_	18	_	ns
	Turn-off time	t _{off}	Duty ≤ 1%, t _w = 10 μs	ı	65	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \approx -80 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -16 \text{ A}$	_	48		nC
Gate-source charge		Q _{gs}		_	29		nC
Gate-drain ("miller") charge		Q _{gd}		_	19	_	nC

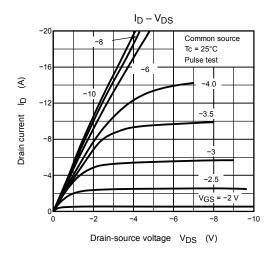
Source-Drain Rating and Characteristics (Ta = 25°C)

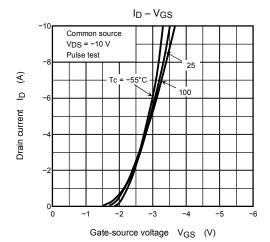
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	-16	А
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	-64	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = -16 A, V _{GS} = 0 V	_	_	1.7	V
Reverse recovery time	t _{rr}	I _{DR} = -16 A, V _{GS} = 0 V		160	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} /dt = 50 A/μs	_	0.5	_	μC

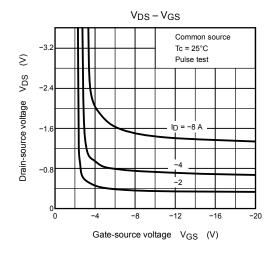
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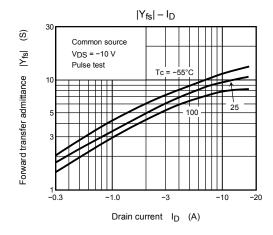


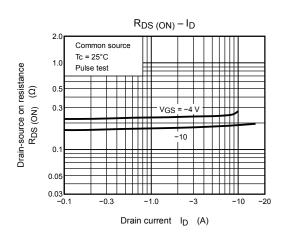


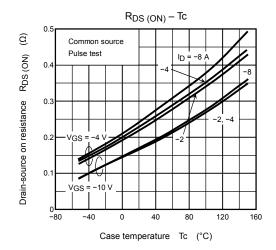


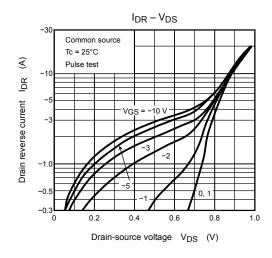


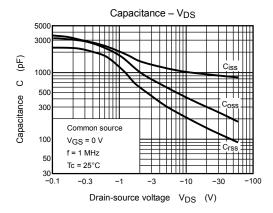


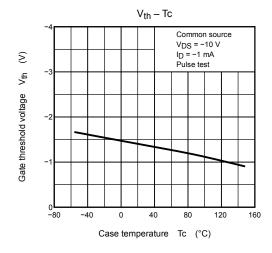


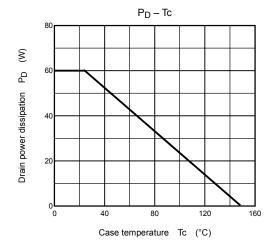


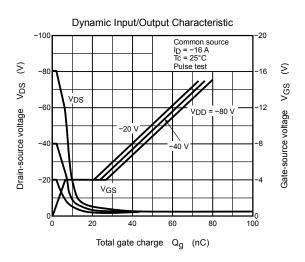




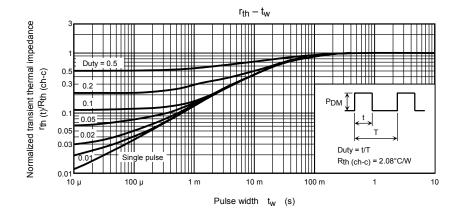


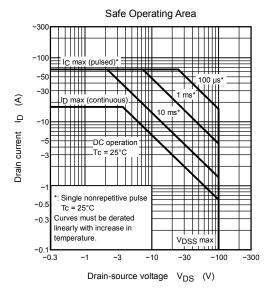


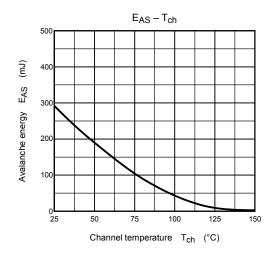


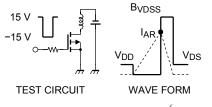


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$$R_G = 25 \Omega$$

 $V_{DD} = -25 \text{ V}, L = 1.84 \text{ mH}$ $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$

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